

October 2007

FAN3100 Single 2A High-Speed, Low-Side Gate Driver

Features

- 3A Peak Sink/Source at V_{DD} = 12V
- 4.5 to 18V Operating Range
- Dual-Logic Inputs Allow Configuration as Non-Inverting or Inverting with Enable Function
- Internal Resistors Turn Driver Off If No Inputs
- 13ns Typical Rise Time and 9ns Typical Fall-Time with 1nF Load
- Choice of TTL or CMOS Input Thresholds
- MillerDrive[™] Technology
- Typical Propagation Delay Time Under 20ns with Input Falling or Rising
- 6-Lead 2x2mm MLP or 5-Pin SOT23 Packages
- Rated from –40°C to 125°C Ambient

Applications

- Switch-Mode Power Supplies
- High-Efficiency MOSFET Switching
- Synchronous Rectifier Circuits
- DC-to-DC Converters
- Motor Control

Description

The FAN3100 2A gate driver is designed to drive an N-channel enhancement-mode MOSFET in low-side switching applications by providing high peak current pulses during the short switching intervals. The driver is available with either TTL (FAN3100T) or CMOS (FAN3100C) input thresholds. Internal circuitry provides an under-voltage lockout function by holding the output low until the supply voltage is within the operating range. The FAN3100 delivers fast MOSFET switching performance, which helps maximize efficiency in high-frequency power converter designs.

FAN3100 drivers incorporate MillerDrive™ architecture for the final output stage. This bipolar-MOSFET combination provides high peak current during the Miller plateau stage of the MOSFET turn-on / turn-off process to minimize switching loss, while providing rail-to-rail voltage swing and reverse current capability.

The FAN3100 also offers dual inputs that can be configured to operate in non-inverting or inverting mode and allow implementation of an enable function. If one or both inputs are left unconnected, internal resistors bias the inputs such that the output is pulled low to hold the power MOSFET off.

The FAN3100 is available in a lead-free finish 2x2mm 6-lead Molded Leadless Package (MLP), for smallest size with excellent thermal performance, or industry-standard 5-pin SOT23.

Functional Pin Configurations

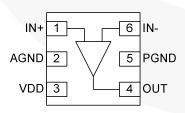


Figure 1. 2x2mm 6-Lead MLP (Top View)

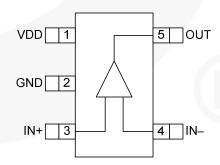


Figure 2. SOT23-5 (Top View)

Ordering Information

Part Number	Input Threshold	Thermal Resistance		Dookogo	Packing	
Part Number	input Threshold	Θ _{JL} ⁽¹⁾	Θ _{JA} ⁽²⁾	Package	Method	
FAN3100CMPX	CMOS	4.5°C/W	58 - 120°C/W ⁽³⁾	6-Lead 2x2mm MLP	Tape & Reel	
FAN3100CSX	CMOS	95°C/W	150 - 248°C/W ⁽³⁾	5-Pin SOT23	Tape & Reel	
FAN3100TMPX	TTL	4.5°C/W	58 - 120°C/W ⁽³⁾	6-Lead 2x2mm MLP	Tape & Reel	
FAN3100TSX	TTL	95°C/W	150 - 248°C/W ⁽³⁾	5-Pin SOT23	Tape & Reel	

Notes:

- Typical Θ_{JL} is specified from semiconductor junction to pin 5 lead. Typical Θ_{JA} is dependent on the PCB design and operating conditions, such as air flow. The range of values covers a variety of operating conditions utilizing natural convection with no heatsink on the package.
- This typical range is an estimate; actual values depend on the application.
- All packages are lead free per JEDEC: J-STD-020B standard.

Pin Definitions

SOT23 Pin #	MLP Pin#	Name	Pin Description
1	3	VDD	Supply Voltage. Provides power to the IC.
	2	AGND	Analog ground for input signals (MLP only). Connect to PGND underneath the IC.
2		GND	Ground (SOT-23 only). Common ground reference for input and output circuits.
3	1	IN+	Non-Inverting Input. Connect to VDD to enable output.
4	6	IN-	Inverting Input. Connect to AGND or PGND to enable output.
5	4	OUT	Gate Drive Output : Held low unless required inputs are present and V _{DD} is above UVLO threshold.
	Pad	P1	Thermal Pad (MLP only). Exposed metal on the bottom of the package; may be left floating or connected to PGND, but NOT suitable for carrying current.
	5	PGND	Power Ground (MLP only). For output drive circuit; separates switching noise from inputs.

Output Logic with Dual-Input Configuration

IN+	IN-	OUT
0 ⁽⁴⁾	0	0
0 ⁽⁴⁾	1 ⁽⁴⁾	0
1	0	1
1	1 ⁽⁴⁾	0

Note:

4. Default input signal if no external connection is made.

Block Diagrams

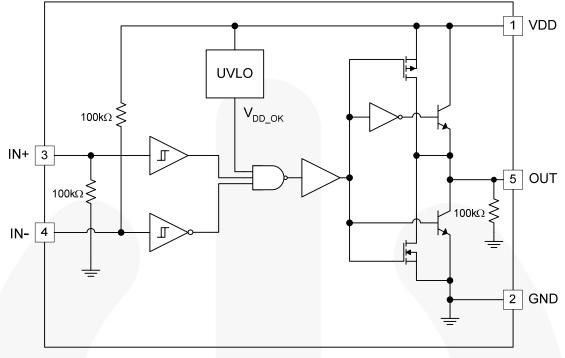


Figure 3. Simplified Block Diagram (SOT23 Pin-out)

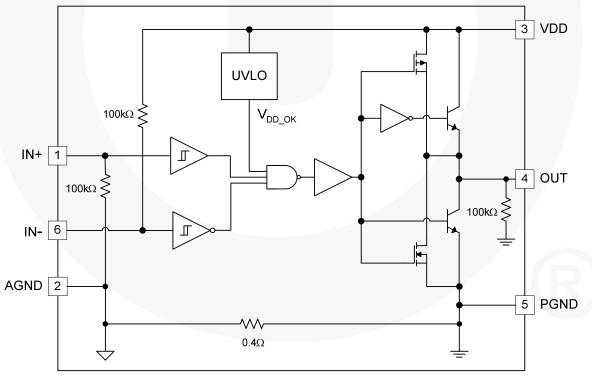


Figure 4. Simplified Block Diagram (MLP Pin-out)

Absolute Maximum Ratings

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol		Min.	Max.	Unit	
	VDD to PGND		-0.3	20.0	V
V_{DD}	Voltage on IN+ and IN- to	PGND - 0.3	V _{DD} + 0.3	V	
	Voltage on OUT to PGND	PGND - 0.3	V _{DD} + 0.3	V	
T _L	Lead Soldering Temperature (10 seconds)			+260	°C
T_J	Junction Temperature		+150	°C	
T _{STG}	Storage Temperature	-65	+150	°C	
ESD	Electrostatic Discharge	Human Body Model, JEDEC JESD22-A114	4		kV
ESD	Protection Level	Charged Device Model, JEDEC JESD22-C101	750		V

Recommended Operating Conditions

The Recommended Operating Conditions table defines the conditions for actual device operation. Recommended operating conditions are specified to ensure optimal performance to the datasheet specifications. Fairchild does not recommend exceeding them or designing to Absolute Maximum Ratings.

Symbol	Parameter	Min.	Max.	Unit
V_{DD}	Supply Voltage Range	4.5	18.0	V
V _{IN}	Input Voltage IN+, IN-	0	V_{DD}	V
T _A	Operating Ambient Temperature	-40	+125	°C

Pin Configurations

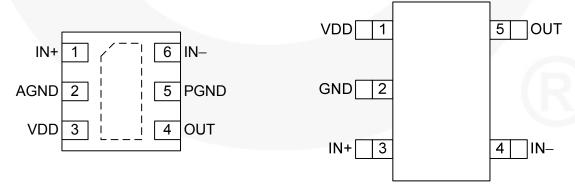


Figure 5. 2x2mm 6-Lead MLP (Top View)

Figure 6. SOT23-5 (Top View)

Electrical Characteristics

Unless otherwise noted, V_{DD} = 12V, T_J = -40°C to +125°C. Currents are defined as positive into the device and negative out of the device.

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Supply			•	,		
V_{DD}	Operating Range		4.5		18.0	V
	Supply Current	FAN3100C		0.20	0.35	mA
I _{DD}	Inputs/EN Not Connected	FAN3100T		0.5	8.0	mA
V _{ON}	Turn-On Voltage		3.5	3.9	4.3	V
V_{OFF}	Turn-Off Voltage		3.3	3.7	4.1	V
Inputs (FA	N3100T)					
V _{INL_T}	IN+, IN- Logic Low Voltage, Maximum		0.8			V
V _{INH_T}	IN+, IN- Logic High Voltage, Minimum				2.0	V
I _{IN+}	Non-inverting Input	IN from 0 to V _{DD}	-1		175	μA
I _{IN-}	Inverting Input	IN from 0 to V _{DD}	-175		1	μA
V _{HYS}	IN+, IN- Logic Hysteresis Voltage		0.2	0.4	0.8	V
Inputs (FA	N3100C)					
V _{INL_C}	IN+, IN- Logic Low Voltage		30			%V _{DD}
V _{INH_C}	IN+, IN- Logic High Voltage				70	%V _{DD}
I _{INL}	IN Current, Low	IN from 0 to V _{DD}	-1		175	μΑ
I _{INH}	IN Current, High	IN from 0 to V _{DD}	-175		1	μA
V _{HYS_C}	IN+, IN- Logic Hysteresis Voltage			17		%V _{DD}
Output						
I _{SINK}	OUT Current, Mid-Voltage, Sinking ⁽⁵⁾	OUT at $V_{DD}/2$, $C_{LOAD} = 0.1 \mu F$, $f = 1 kHz$		2.5		А
I _{SOURCE}	OUT Current, Mid-Voltage, Sourcing ⁽⁵⁾	OUT at $V_{DD}/2$, $C_{LOAD} = 0.1 \mu F$, $f = 1 kHz$		-1.8		Α
I _{PK_SINK}	OUT Current, Peak, Sinking ⁽⁵⁾	$C_{LOAD} = 0.1 \mu F$, $f = 1 kHz$		3		Α
I _{PK_SOURCE}	OUT Current, Peak, Sourcing ⁽⁵⁾	C _{LOAD} = 0.1µF, f = 1kHz		-3		Α
t _{RISE}	Output Rise Time ⁽⁶⁾	C _{LOAD} = 1000pF		13	20	ns
t _{FALL}	Output Fall Time ⁽⁶⁾	C _{LOAD} = 1000pF		9	14	ns
t _{D1} , t _{D2}	Output Prop. Delay, CMOS Inputs ⁽⁶⁾	0 - 12V _{IN} ; 1V/ns Slew Rate	7	15	28	ns
t_{D1},t_{D2}	Output Prop. Delay, TTL Inputs ⁽⁶⁾	0 - 5V _{IN} ; 1V/ns Slew Rate	9	16	30	ns
I _{RVS}	Output Reverse Current Withstand ⁽⁵⁾			500		mA

Note:

- 5. Not tested in production.
- 6. See Timing Diagrams of Figure 7 and Figure 8.

Timing Diagrams

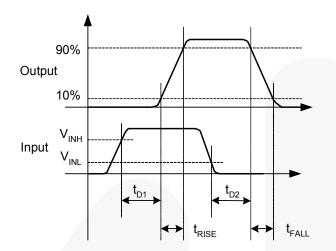


Figure 7. Non-Inverting

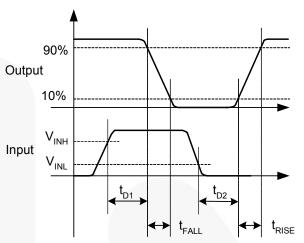
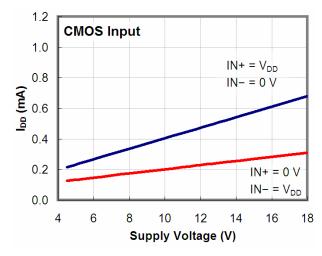


Figure 8. Inverting

Typical Performance Characteristics



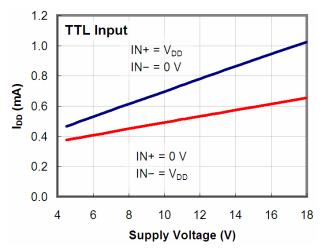
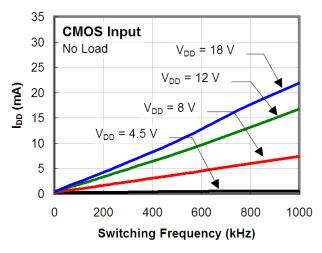


Figure 9. IDD (Static) vs. Supply Voltage

Figure 10. IDD (Static) vs. Supply Voltage



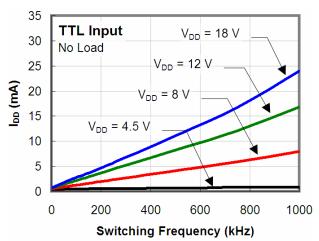
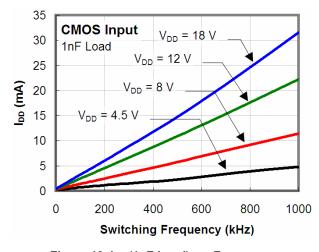


Figure 11. I_{DD} (No-Load) vs. Frequency

Figure 12. I_{DD} (No-Load) vs. Frequency



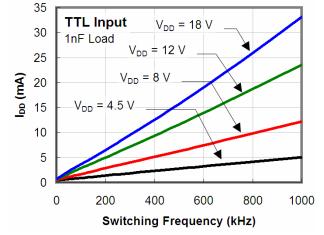


Figure 13. I_{DD} (1nF Load) vs. Frequency

Figure 14. I_{DD} (1nF Load) vs. Frequency

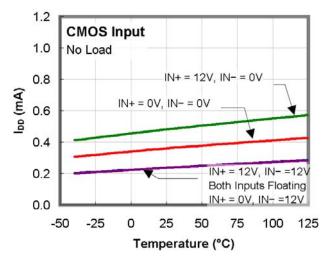


Figure 15. I_{DD} (Static) vs. Temperature

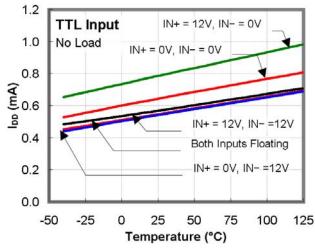


Figure 16. I_{DD} (Static) vs. Temperature

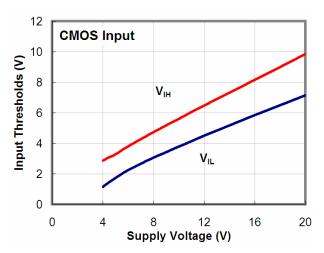


Figure 17. Input Thresholds vs. Supply Voltage

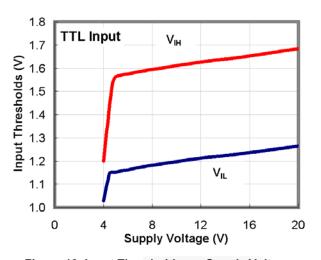


Figure 18. Input Thresholds vs. Supply Voltage

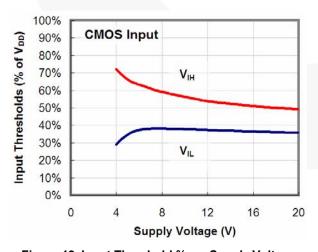


Figure 19. Input Threshold % vs. Supply Voltage

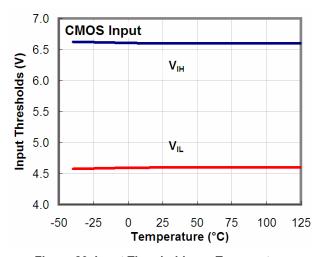


Figure 20. Input Thresholds vs. Temperature

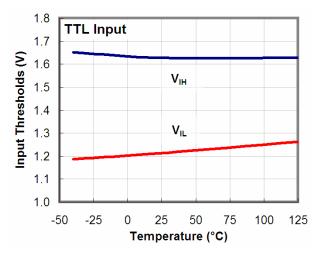


Figure 21. Input Thresholds vs. Temperature

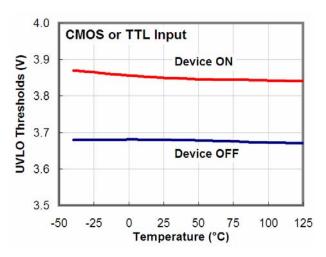


Figure 22. UVLO Thresholds vs. Temperature

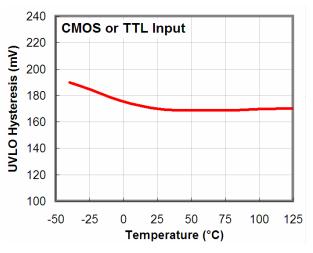


Figure 23. UVLO Hysteresis vs. Temperature

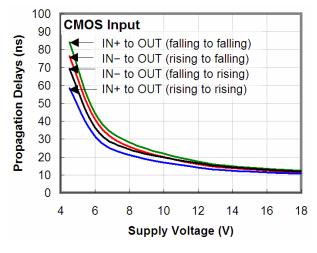


Figure 24. Propagation Delay vs. Supply Voltage

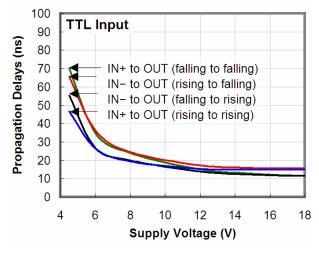
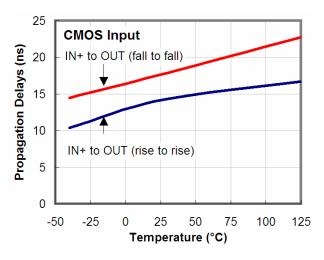


Figure 25. Propagation Delay vs. Supply Voltage



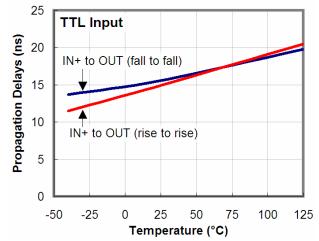
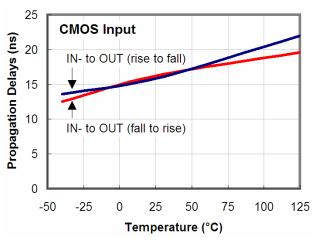


Figure 26. Propagation Delay vs. Temperature

Figure 27. Propagation Delay vs. Temperature



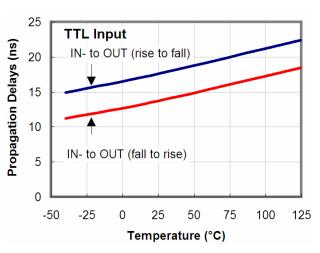
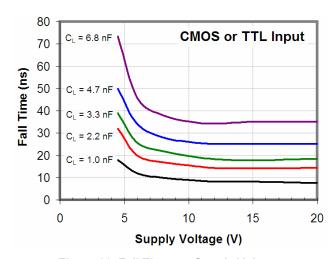


Figure 28. Propagation Delay vs. Temperature

Figure 29. Propagation Delay vs. Temperature



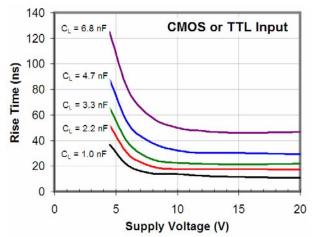


Figure 30. Fall Time vs. Supply Voltage

Figure 31. Rise Time vs. Supply Voltage

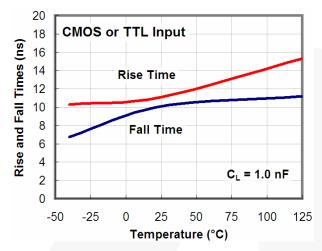
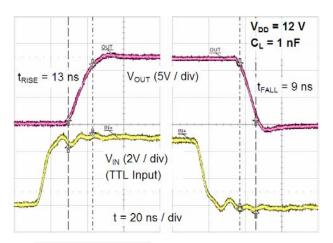


Figure 32. Rise and Fall Time vs. Temperature



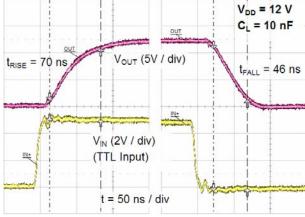


Figure 33. Rise/Fall Waveforms with 1nF Load

Figure 34. Rise/Fall Waveforms with 10nF Load

Applications Information

The FAN3100 offers TTL or CMOS input thresholds. In the FAN3100T, the input thresholds meet industry-standard TTL logic thresholds, independent of the V_{DD} voltage, and there is a hysteresis voltage of approximately 0.4V. These levels permit the inputs to be driven from a range of input logic signal levels for which a voltage over 2V is considered logic high. The driving signal for the TTL inputs should have fast rising and falling edges with a slew rate of 6V/ μ s or faster, so the rise time from 0 to 3.3V should be 550ns or less. With reduced slew rate, circuit noise could cause the driver input voltage to exceed the hysteresis voltage and retrigger the driver input, causing erratic operation.

In the FAN3100C, the logic input thresholds are dependent on the V_{DD} level and, with V_{DD} of 12V, the logic rising edge threshold is approximately 55% of V_{DD} and the input falling edge threshold is approximately 38% of V_{DD} . The CMOS input configuration offers a hysteresis voltage of approximately 17% of V_{DD} . The CMOS inputs can be used with relatively slow edges (approaching DC) if good decoupling and bypass techniques are incorporated in the system design to prevent noise from violating the input voltage hysteresis window. This allows setting precise timing intervals by fitting an R-C circuit between the controlling signal and the IN pin of the driver. The slow rising edge at the IN pin of the driver introduces a delay between the controlling signal and the OUT pin of the driver.

MillerDrive™ Gate Drive Technology

FAN3100 drivers incorporate the MillerDrive™ architecture shown in Figure 35 for the output stage, a combination of bipolar and MOS devices capable of providing large currents over a wide range of supply voltage and temperature variations. The bipolar devices carry the bulk of the current as OUT swings between 1/3 to 2/3 V_{DD} and the MOS devices pull the output to the high or low rail.

The purpose of the MillerDrive™ architecture is to speed up switching by providing the highest current during the Miller plateau region when the gate-drain capacitance of the MOSFET is being charged or discharged as part of the turn-on / turn-off process. For applications that have zero voltage switching during the MOSFET turn-on or turn-off interval, the driver supplies high peak current for fast switching even though the Miller plateau is not present. This situation often occurs in synchronous rectifier applications because the body diode is generally conducting before the MOSFET is switched on.

The output pin slew rate is determined by V_{DD} voltage and the load on the output. It is not user adjustable, but if a slower rise or fall time at the MOSFET gate is needed, a series resistor can be added.

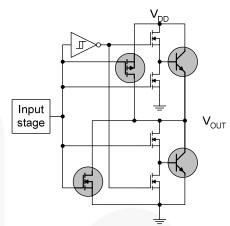


Figure 35. MillerDrive™ Output Architecture

Under-Voltage Lockout

The FAN3100 start-up logic is optimized to drive ground referenced N-channel MOSFETs with a under-voltage lockout (UVLO) function to ensure that the IC starts up in an orderly fashion. When V_{DD} is rising, yet below the 3.9V operational level, this circuit holds the output low, regardless of the status of the input pins. After the part is active, the supply voltage must drop 0.2V before the part shuts down. This hysteresis helps prevent chatter when low V_{DD} supply voltages have noise from the power switching. This configuration is not suitable for driving high-side P-channel MOSFETs because the low output voltage of the driver would turn the P-channel MOSFET on with V_{DD} below 3.9V.

VDD Bypass Capacitor Guidelines

To enable this IC to turn a power device on quickly, a local, high-frequency, bypass capacitor C_{BYP} with low ESR and ESL should be connected between the VDD and GND pins with minimal trace length. This capacitor is in addition to bulk electrolytic capacitance of $10\mu\text{F}$ to $47\mu\text{F}$ often found on driver and controller bias circuits.

A typical criterion for choosing the value of C_{BYP} is to keep the ripple voltage on the V_{DD} supply $\leq 5\%$. Often this is achieved with a value ≥ 20 times the equivalent load capacitance C_{EQV} , defined here as Q_{gate}/V_{DD} . Ceramic capacitors of $0.1\mu F$ to $1\mu F$ or larger are common choices, as are dielectrics, such as X5R and X7R, which have good temperature characteristics and high pulse current capability.

If circuit noise affects normal operation, the value of C_{BYP} may be increased to 50-100 times the C_{EQV} , or C_{BYP} may be split into two capacitors. One should be a larger value, based on equivalent load capacitance, and the other a smaller value, such as 1-10nF, mounted closest to the VDD and GND pins to carry the higher-frequency components of the current pulses.

Layout and Connection Guidelines

The FAN3100 incorporates fast reacting input circuits, short propagation delays, and powerful output stages capable of delivering current peaks over 2A to facilitate voltage transition times from under 10ns to over 100ns. The following layout and connection guidelines are strongly recommended:

- Keep high-current output and power ground paths separate from logic input signals and signal ground paths. This is especially critical when dealing with TTL-level logic thresholds.
- Keep the driver as close to the load as possible to minimize the length of high-current traces. This reduces the series inductance to improve highspeed switching, while reducing the loop area that can radiate EMI to the driver inputs and other surrounding circuitry.
- The FAN3100 is available in two packages with slightly different pinouts, offering similar performance. In the 6-pin MLP package, Pin 2 is internally connected to the input analog ground and should be connected to power ground, Pin 5, through a short direct path underneath the IC. In the 5-pin SOT23, the internal analog and power ground connections are made through separate, individual bond wires to Pin 2, which should be used as the common ground point for power and control signals.
- Many high-speed power circuits can be susceptible to noise injected from their own output or other external sources, possibly causing output retriggering. These effects can be especially obvious if the circuit is tested in breadboard or non-optimal circuit layouts with long input, enable, or output leads. For best results, make connections to all pins as short and direct as possible.
- The turn-on and turn-off current paths should be minimized as discussed in the following sections.

Figure 36 shows the pulsed gate drive current path when the gate driver is supplying gate charge to turn the MOSFET on. The current is supplied from the local bypass capacitor, C_{BYP} , and flows through the driver to the MOSFET gate and to ground. To reach the high peak currents possible, the resistance and inductance in the path should be minimized. The localized C_{BYP} acts to contain the high peak current pulses within this driver-MOSFET circuit, preventing them from disturbing the sensitive analog circuitry in the PWM controller.

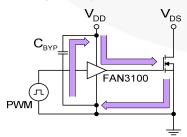


Figure 36. Current Path for MOSFET Turn-On

Figure 37 shows the current path when the gate driver turns the MOSFET off. Ideally, the driver shunts the current directly to the source of the MOSFET in a small circuit loop. For fast turn-off times, the resistance and inductance in this path should be minimized.

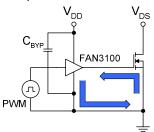


Figure 37. Current Path for MOSFET Turn-Off

Truth Table of Logic Operation

The FAN3100 truth table indicates the operational states using the dual-input configuration. In a non-inverting driver configuration, the IN- pin should be a logic low signal. If the IN- pin is connected to logic high, a disable function is realized, and the driver output remains low regardless of the state of the IN+ pin.

IN+	IN-	OUT
0	0	0
0	1	0
1	0	1
1	1	0

In the non-inverting driver configuration in Figure 38, the IN- pin is tied to ground and the input signal (PWM) is applied to IN+ pin. The IN- pin can be connected to logic high to disable the driver and the output remains low, regardless of the state of the IN+ pin.

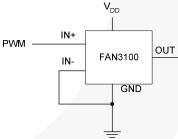


Figure 38. Dual-Input Driver Enabled, Non-Inverting Configuration

In the inverting driver application shown in Figure 39, the IN+ pin is tied high. Pulling the IN+ pin to GND forces the output low, regardless of the state of the IN- pin.

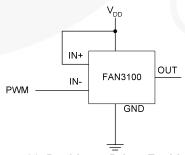


Figure 39. Dual-Input Driver Enabled, Inverting Configuration

Operational Waveforms

At power up, the driver output remains low until the V_{DD} voltage reaches the turn-on threshold. The magnitude of the OUT pulses rises with V_{DD} until steady-state V_{DD} is reached. The non-inverting operation illustrated in Figure 40 shows that the output remains low until the UVLO threshold is reached, then the output is in-phase with the input.

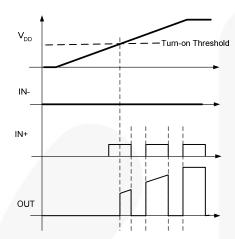


Figure 40. Non-Inverting Start-Up Waveforms

For the inverting configuration of Figure 39, start-up waveforms are shown in Figure 41. With IN+ tied to VDD and the input signal applied to IN-, the OUT pulses are inverted with respect to the input. At power up, the inverted output remains low until the $V_{\rm DD}$ voltage reaches the turn-on threshold, then it follows the input with inverted phase.

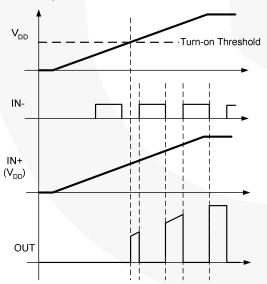


Figure 41. Inverting Start-Up Waveforms

Thermal Guidelines

Gate drivers used to switch MOSFETs and IGBTs at high frequencies can dissipate significant amounts of power. It is important to determine the driver power dissipation and the resulting junction temperature in the application to ensure that the part is operating within acceptable temperature limits.

The total power dissipation in a gate driver is the sum of three components; P_{GATE} , $P_{\text{QUIESCENT}}$, and P_{DYNAMIC} :

$$P_{TOTAL} = P_{GATE} + P_{DYNAMIC}$$
 (1)

Gate Driving Loss: The most significant power loss results from supplying gate current (charge per unit time) to switch the load MOSFET on and off at the switching frequency. The power dissipation that results from driving a MOSFET at a specified gate-source voltage, V_{GS} , with gate charge, Q_{G} , at switching frequency, f_{SW} , is determined by:

$$P_{GATE} = Q_G \cdot V_{GS} \cdot F_{SW}$$
 (2)

Dynamic Pre-drive / Shoot-through Current: A power loss resulting from internal current consumption under dynamic operating conditions, including pin pull-up / pull-down resistors, can be obtained using the graphs in Figure 11 and Figure 12 in Typical Performance Characteristics to determine the current I_{DYNAMIC} drawn from V_{DD} under actual operating conditions:

$$P_{DYNAMIC} = I_{DYNAMIC} \cdot V_{DD}$$
 (3)

Once the power dissipated in the driver is determined, the driver junction temperature rise with respect to the device lead can be evaluated using thermal equation:

$$T_J = P_{TOTAL} \cdot \Theta_{JL} + T_C$$
 (4) where:

T_{.1} = driver junction temperature

 θ_{JL} = thermal resistance from junction to lead

 T_L = lead temperature of device in application.

In a typical forward converter application with 48V input, as shown in Figure 42, the FDS2672 would be a potential MOSFET selection. The typical gate charge would be 32nC with $V_{GS} = V_{DD} = 10V$. Using a TTL input driver at a switching frequency of 500kHz, the total power dissipation can be calculated as:

$$P_{GATE} = 32nC \cdot 10V \cdot 500kHz = 0.160W$$
 (5)

$$P_{DYNAMIC} = 6.5 \text{mA} \cdot 10 \text{V} = 0.065 \text{W}$$
 (6)

$$P_{TOTAL} = 0.225W \tag{7}$$

The 5-pin SOT23 has a junction-to-lead thermal resistance $\theta_{JL} = 95^{\circ}\text{C/W}$. In a system application, the localized temperature around the lead of the device is a function of the layout and construction of the PCB along with airflow across the surfaces. To ensure reliable operation, the maximum junction temperature of the device must be prevented from exceeding the maximum rating of 150°C; with 80% derating, T_J would be limited to 120°C. Rearranging Equation 4 determines of the maximum lead temperature at the PCB surface to maintain the junction temperature below 120°C:

$$T_{L} = T_{J} - P_{TOTAL} \cdot \Theta_{JL}$$
 (8)

$$T_L = 120^{\circ}C - 0.225W \cdot 95^{\circ}C/W = 99^{\circ}C$$
 (9)

For comparison purposes, replace the 5-pin SOT23 used in the previous example with the 6-pin MLP package with θ_{JL} = 4.5°C/W referenced to Pin 5. The 6-pin MLP package can operate with a lead temperature on the PCB surface of 118°C, while maintaining the junction temperature below 120°C. This illustrates that the physically smaller MLP package with thermal pad offers a more conductive path to remove the heat from the driver. Consider the tradeoffs between reducing overall circuit size with junction temperature reduction for increased reliability.

Typical Application Diagrams

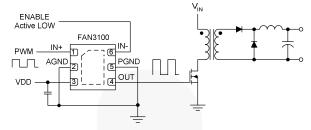


Figure 42. Forward Converter, Primary-Side Gate Drive (MLP Package Shown)

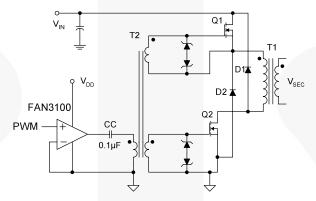


Figure 43. Driver for Two-Transistor Forward Converter Gate Transformer

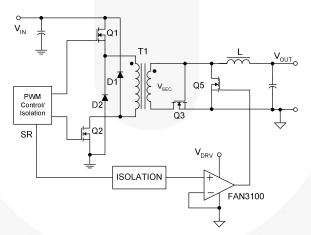


Figure 44. Secondary Synchronous Rectifier Driver

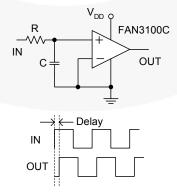
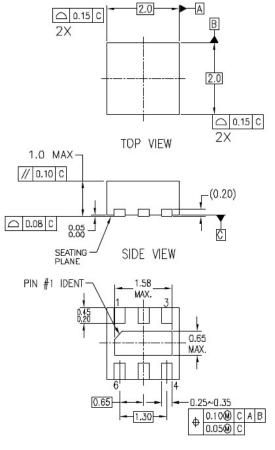


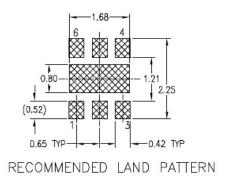
Figure 45. Programmable Time Delay Using CMOS Input

Table 1. Related Products

Part Number	Туре	Gate Drive (Sink/Src)	Input Threshold	Logic	Package
FAN3100C	Single 2A	+2A / -1.5A	смоѕ	One Channel of Dual-Input/Single-Output	SOT23-5, MLP6
FAN3100T	Single 2A	+2A / -1.5A	TTL	One Channel of Dual-Input/Single-Output	SOT23-5, MLP6
FAN3226C	Dual 2A	+2A / -1.5A	CMOS	Dual Inverting Channels + Dual Enable	SOIC8, MLP8
FAN3226T	Dual 2A	+2A / -1.5A	TTL	Dual Inverting Channels + Dual Enable	SOIC8, MLP8
FAN3227C	Dual 2A	+2A / -1.5A	CMOS	Dual Non-Inverting Channels + Dual Enable	SOIC8, MLP8
FAN3227T	Dual 2A	+2A / -1.5A	TTL	Dual Non-Inverting Channels + Dual Enable	SOIC8, MLP8
FAN3228C	Dual 2A	+2A / -1.5A	CMOS	Two Channels of Dual-Input/Single-Output, Pin Config.1	SOIC8, MLP8
FAN3228T	Dual 2A	+2A / -1.5A	TTL	Two Channels of Dual-Input/Single-Output, Pin Config.1	SOIC8, MLP8
FAN3229C	Dual 2A	+2A / -1.5A	CMOS	Two Channels of Dual-Input/Single-Output, Pin Config.2	SOIC8, MLP8
FAN3229T	Dual 2A	+2A / -1.5A	TTL	Two Channels of Dual-Input/Single-Output, Pin Config.2	SOIC8, MLP8
FAN3223C	Dual 4A	+4A / -3A	CMOS	Dual Inverting Channels + Dual Enable	SOIC8, MLP8
FAN3223T	Dual 4A	+4A / -3A	TTL	Dual Inverting Channels + Dual Enable	SOIC8, MLP8
FAN3224C	Dual 4A	+4A / -3A	CMOS	Dual Non-Inverting Channels + Dual Enable	SOIC8, MLP8
FAN3224T	Dual 4A	+4A / -3A	TTL	Dual Non-Inverting Channels + Dual Enable	SOIC8, MLP8
FAN3225C	Dual 4A	+4A / -3A	CMOS	Two Channels of Dual-Input/Single-Output	SOIC8, MLP8
FAN3225T	Dual 4A	+4A / -3A	TTL	Two Channels of Dual-Input/Single-Output SOIC8, MLP8	

Physical Dimensions





BOTTOM VIEW

NOTES:

- A. CONFORMS TO JEDEC REGISTRATION MO-229, VARIATION VCCC, DATED 11/2001
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994

MLP06BrevA

Figure 46. 2x2mm, 6-Lead Molded Leadless Package (MLP)

Physical Dimensions (Continued) **SYMM** 3.00 2.80 Α **-** 0.95 -- 0.95 5 В 3.00 2.60 1.70 1.50 2.60 (0.30)1.00 0.50 0.30 0.95 ⊕ 0.20∭ C A B 1.90 0.70 **TOP VIEW** LAND PATTERN RECOMMENDATION SEE DETAIL A 1.30 1.45 MAX 0.90 0.15 0.05 0.22 С 80.0 ○ 0.10 C NOTES: UNLESS OTHEWISE SPECIFIED A) THIS PACKAGE CONFORMS TO JEDEC MO-178, ISSUE B, VARIATION AA, B) ALL DIMENSIONS ARE IN MILLIMETERS. **GAGE PLANE** C) MA05Brev5 0.25 0.55 0.35 SEATING PLANE 0.60 REF Figure 47. 5-Lead SOT-23





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Green FPS™ Green FPS™ e-Series™ GTO™ i-Lo™ IntelliMAX™ ISOPLANAR™ MegaBuck™ MICROCOUPLER™ MicroFET™

MicroPak™ MillerDrive™ Motion-SPM™ OPTOLOGIC® OPTOPLANAR® PDP-SPM™ Power220®

Power247® POWEREDGE® Power-SPM™ PowerTrench® Programmable Active Droop™ QFET[®] QS™ QT Optoelectronics™ Quiet Series™ RapidConfigure™ SMART START™ SPM® STEALTH™

SuperFET™ SuperSOT™_3 SuperSOT™-6 SuperSOT™-8 SyncFET™ The Power Franchise®

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